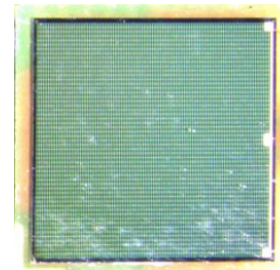


Characterization of the DUNE photodetectors and study of the event burst phenomenon

Tommaso Giammaria
on behalf of the DUNE collaboration



LIDINE2021:Light Detection In Noble Elements

16/09/2021

The DUNE experiment

Deep Underground Neutrino Experiment

- Broad-band neutrino beam (subGeV-10 GeV)
- Longest baseline accelerator experiment (1285 km)
- Both $\nu_\mu(\bar{\nu}_\mu)$ disappearance and $\nu_e(\bar{\nu}_e)$ appearance

DUNE

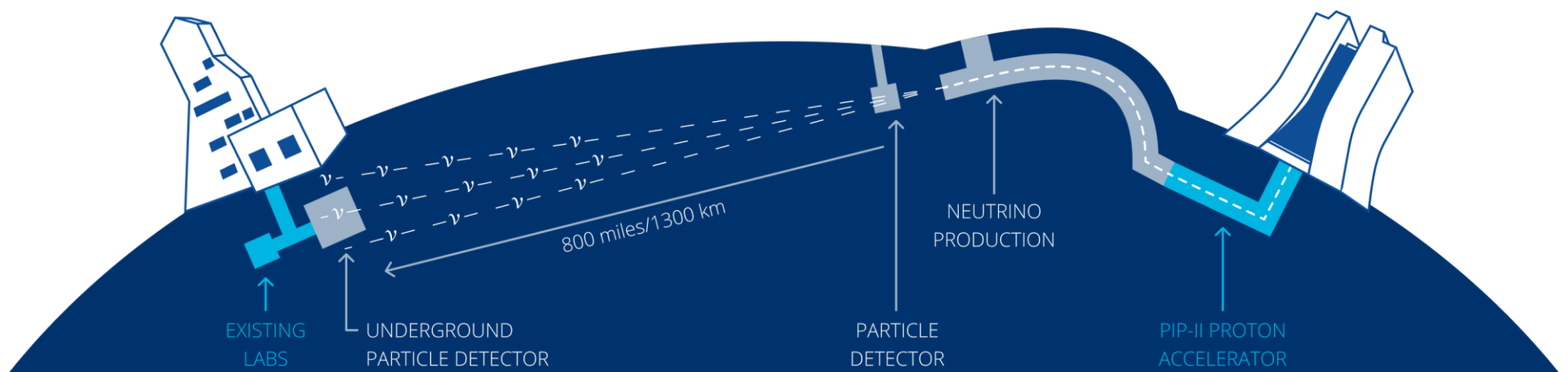
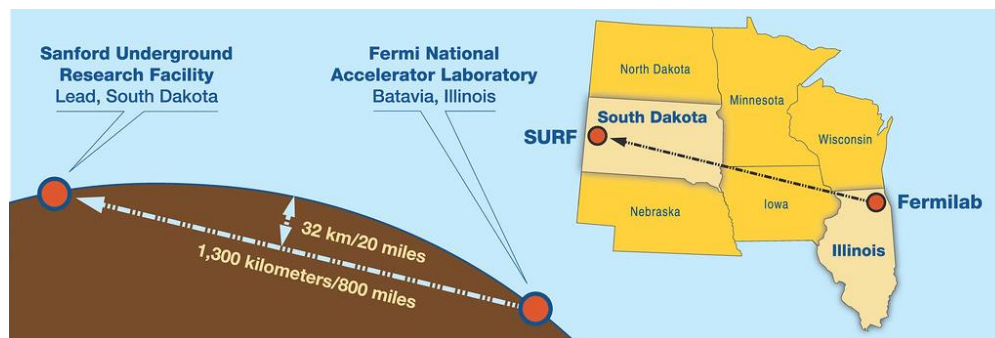
INFN

Istituto Nazionale di Fisica Nucleare

Università degli Studi di Ferrara

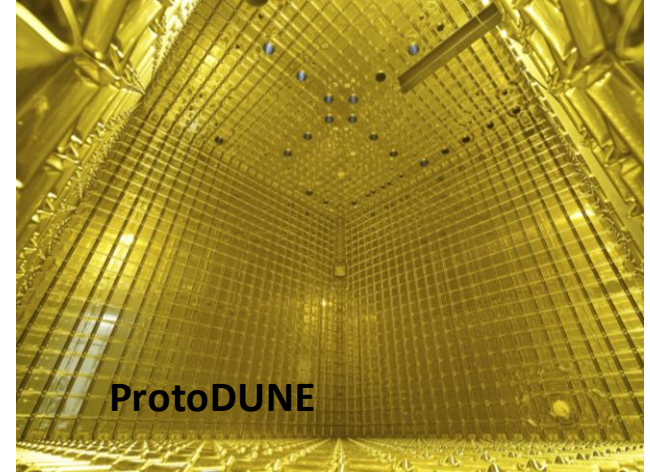
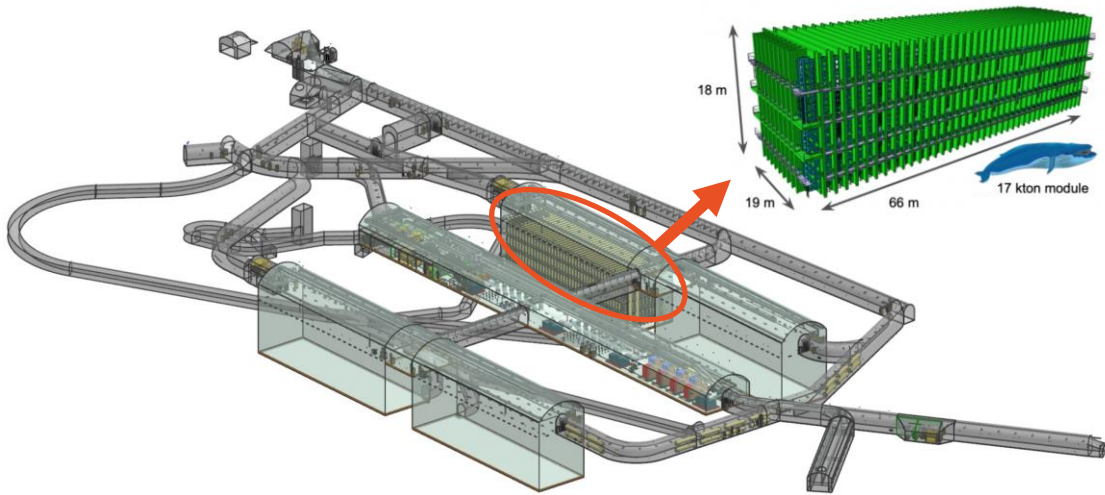
Aims of DUNE:

- CP violating phase
- Mixing angles θ_{13}, θ_{23}
- $\Delta m_{1,3}^2$ (mass ordering, 5σ)
- Supernova neutrino bursts
- Proton decay



Photodetection system for ProtoDUNE2-SP

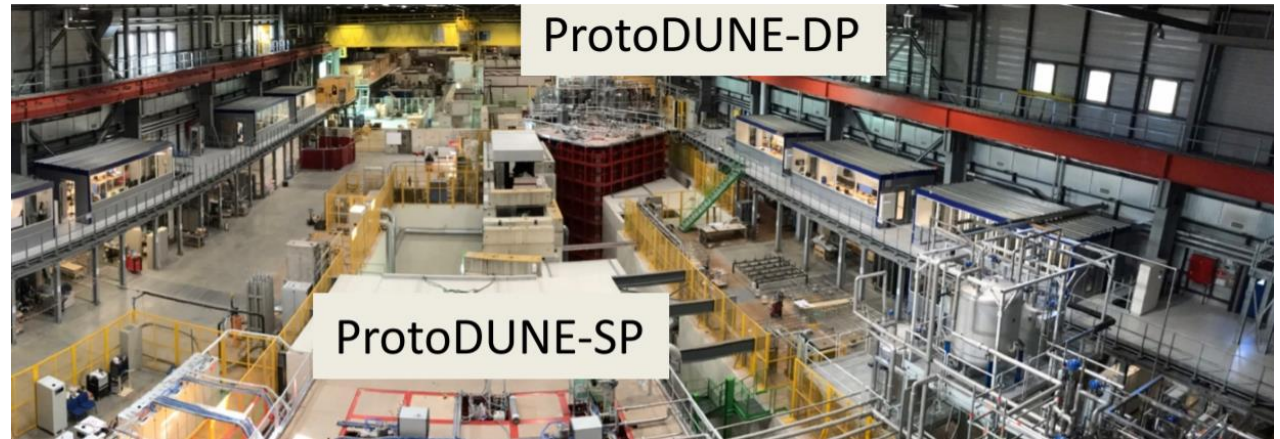
DUNE Far Detector (FD): 4x new generation LArTPCs (17-kton)



ProtoDUNE2-SP

will employ modern technologies

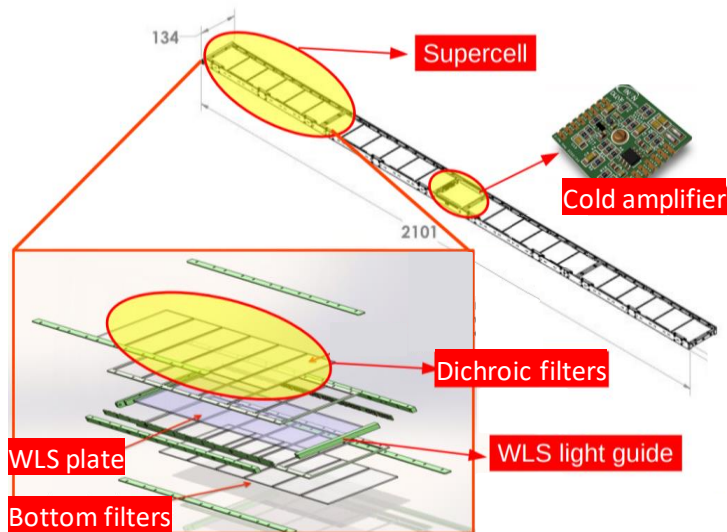
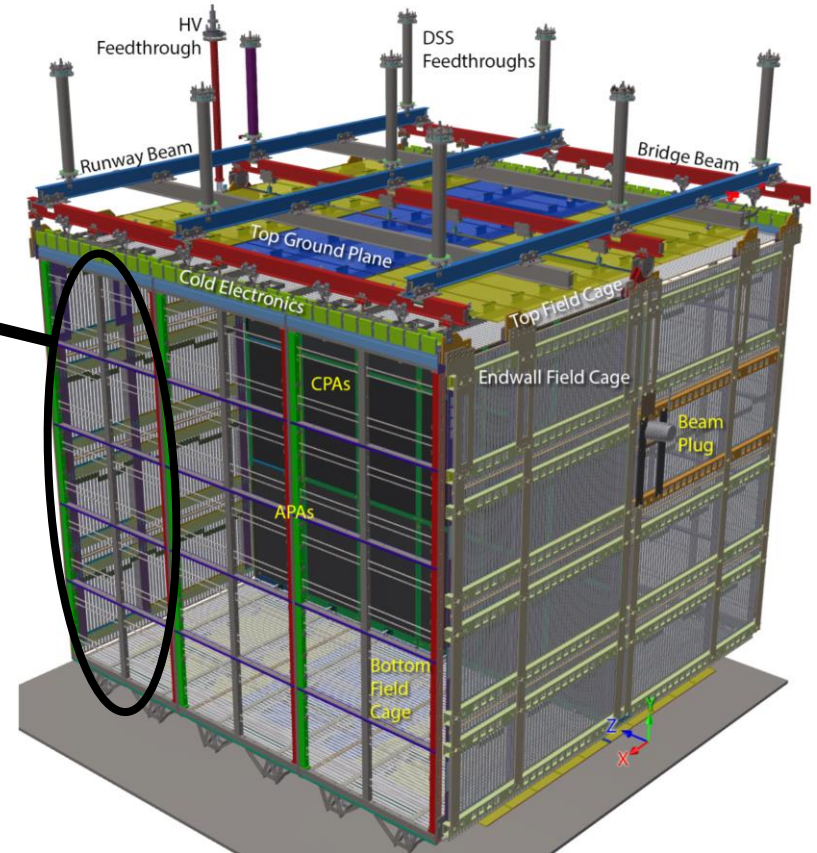
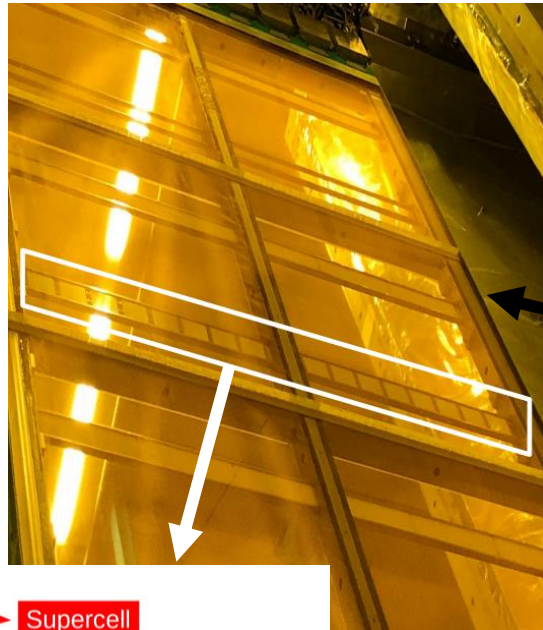
Among these:
Silicon
Photomultipliers
(**SiPMs**) for PD



Photodetection system for ProtoDUNE2-SP

ProtoDUNE2-SP PD system design:

- massive usage of SiPM photosensors
- install 6000 SiPM in 30 X-ARAPUCA modules (3 APA)



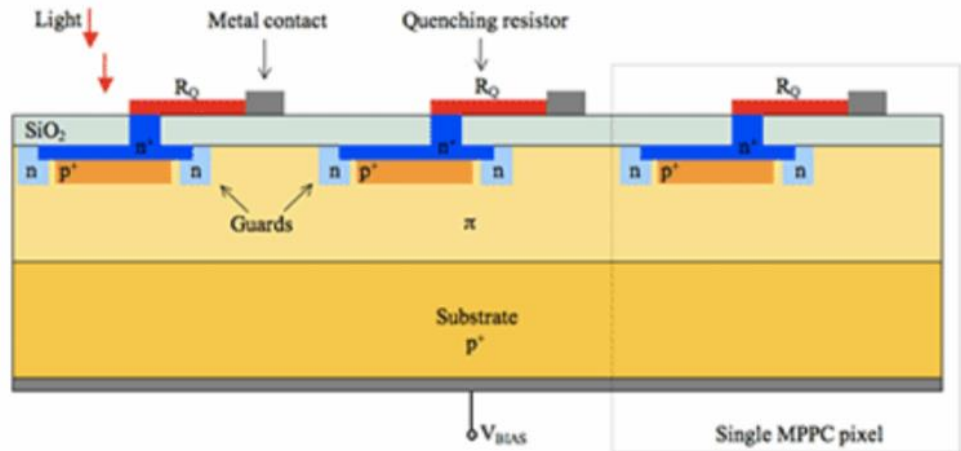
- SiPMs encapsulated in arrays of 6 units
- Modules divided in supercells along the APA
- Cold amplifier to handle signals from the neighboring supercells

SiPMs for low photon count applications

SiPM = matrix of single photon avalanche photodiodes (SPADs)

Properties:

- mechanical robustness
- reduced cost and size
- magnetic field immunity
- high sensitivity
- high dynamic range



Dark Count Rate (DCR):

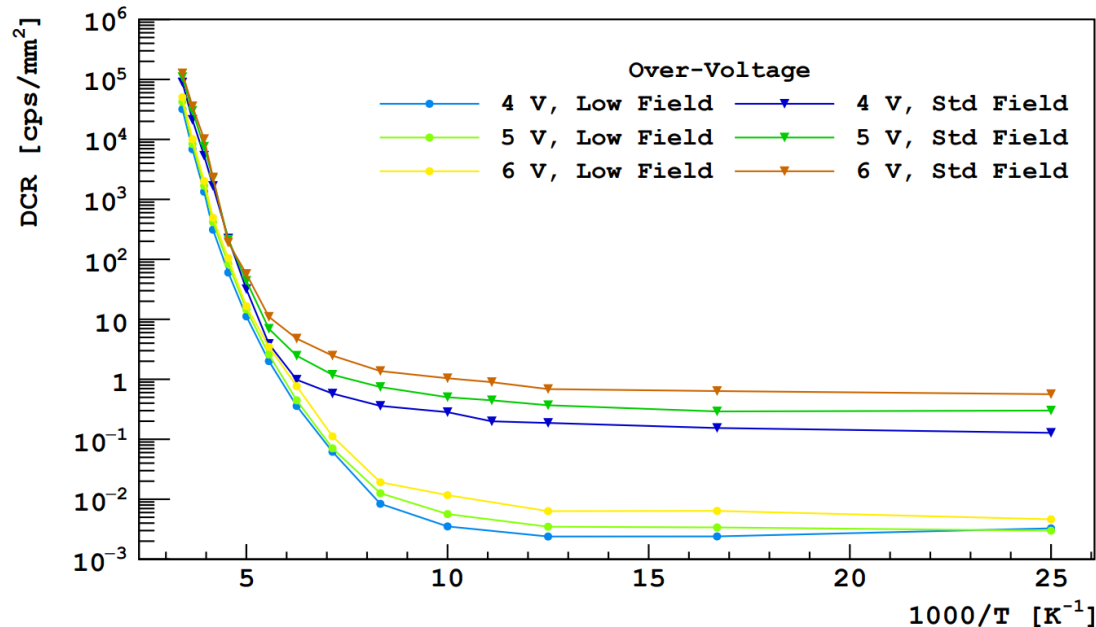
- background signal happening also in absolute darkness
- main drawback for low photon count applications
- high at room T (~ 100 kHz/mm²)
- drops to few tens of mHz/mm² at cryogenic T

SiPMs for low photon count applications

ProtoDUNE and DUNE SiPM models produced by **two** vendors:

- **Fondazione Bruno Kessler (FBK)**
- **Hamamatsu Photonics K.K. (HPK)**

HAMAMATSU
PHOTON IS OUR BUSINESS



From *Cryogenic Characterization of FBK HD Near-UV Sensitive SiPMs*, by Fabio Acerbi Et Al.

DOI:

10.1109/TED.20

16.2641586

SiPM characterization

Tested SiPMs

Vendor	Pitch	N_{cells}	Package	Design
HPK	50 μm	14331	Surface mount type	Hole wire bond
HPK	75 μm	6364	Surface mount type	Hole wire bond
FBK	30 μm	37300	Chip on board	standard lateral bond, single trench
FBK	50 μm	11188	Chip on board	standard lateral bond, triple trench

All sensors have the same form factor (6 x 6 mm²)

1. **Full-characterization** of single devices (following slides)
2. Characterization of **6-SiPM boards** (ganging test)
3. Mass test, test of a **high number** of SiPMs (need of custom experimental setups to speed-up the tests)

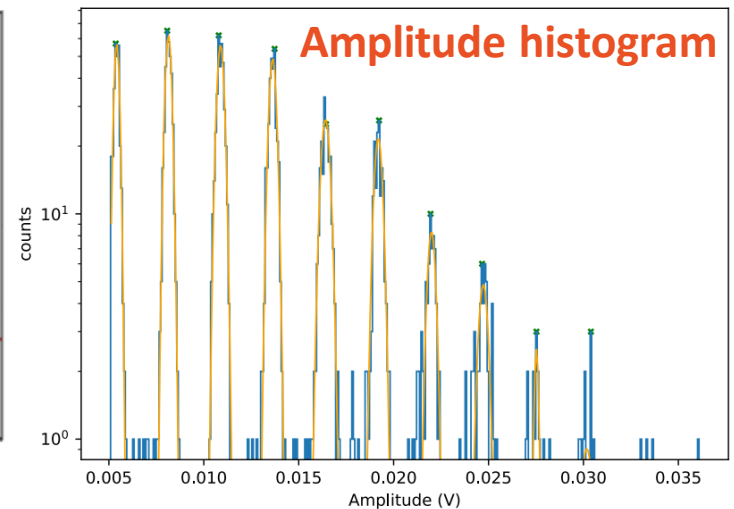
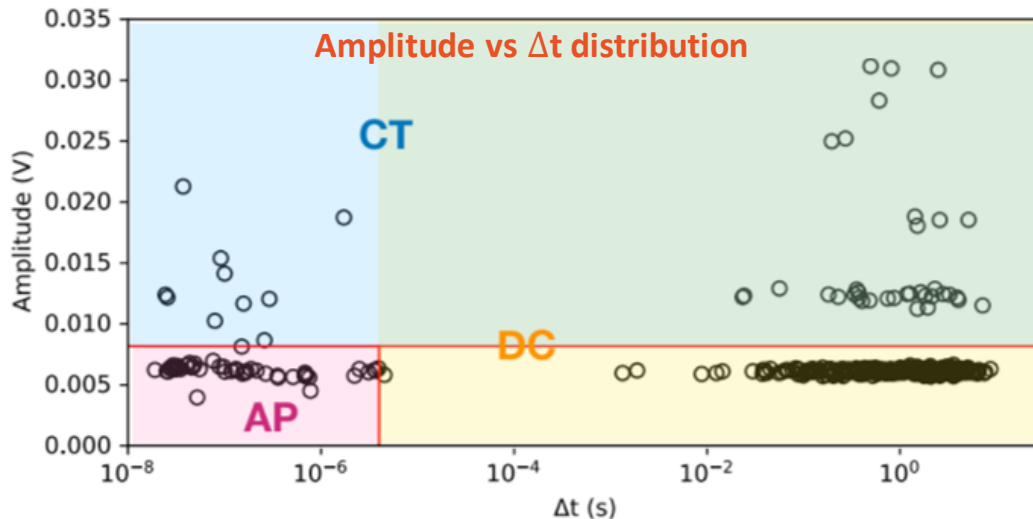
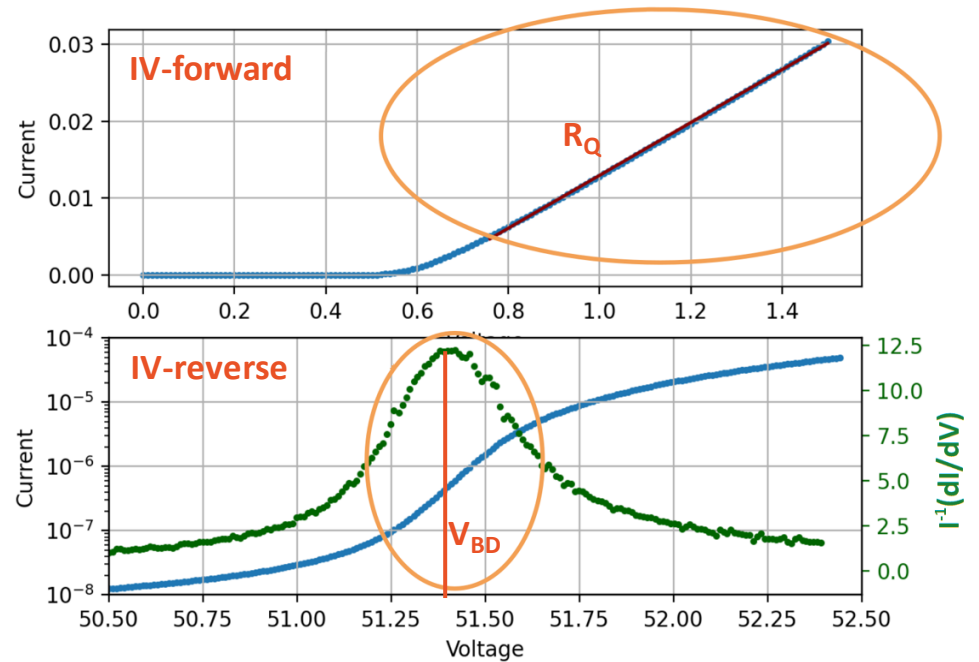
SiPM characterization

Important physical quantities:

- V_{BD} and R_Q
- DCR, AP and CT
- Gain and SNR

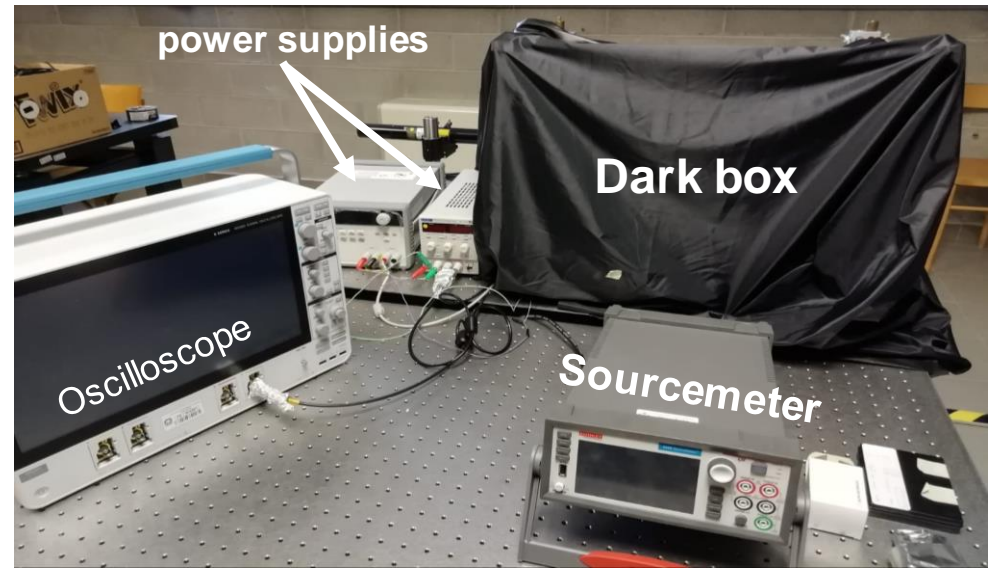
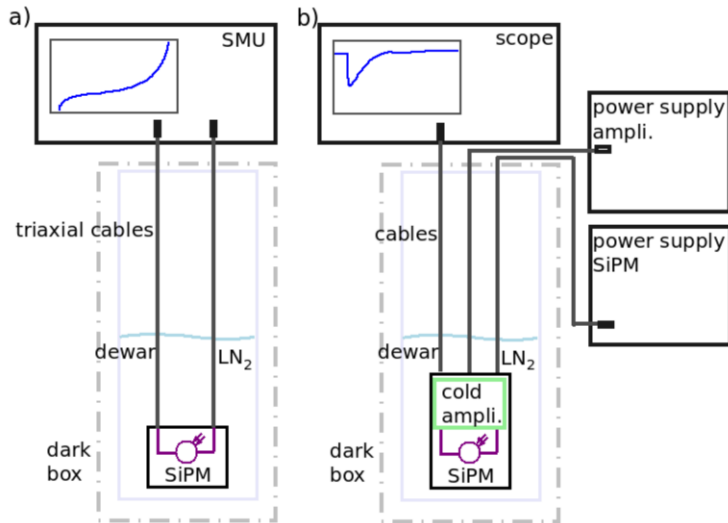
To measure these quantities:

- IV curve
- Dark noise measurement
- LED acquisition



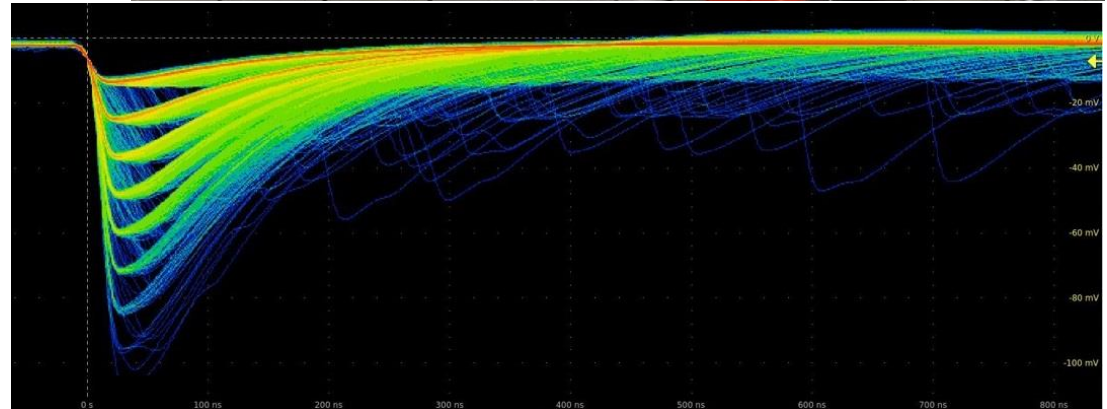
SiPM characterization

All measurements performed at LN₂T, except IV characterization



For Gain (and SNR):

- DCR setup
- Device is illuminated by a LED
- Acquisition triggered on LED pulse



Samples undergo 20 thermal cycles, then we restart the tests (to check long time operation at cryogenic temperatures)

Results: burst discovery

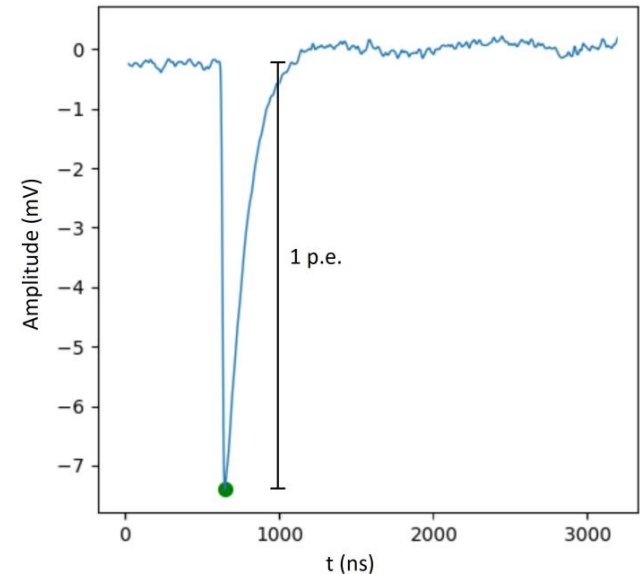
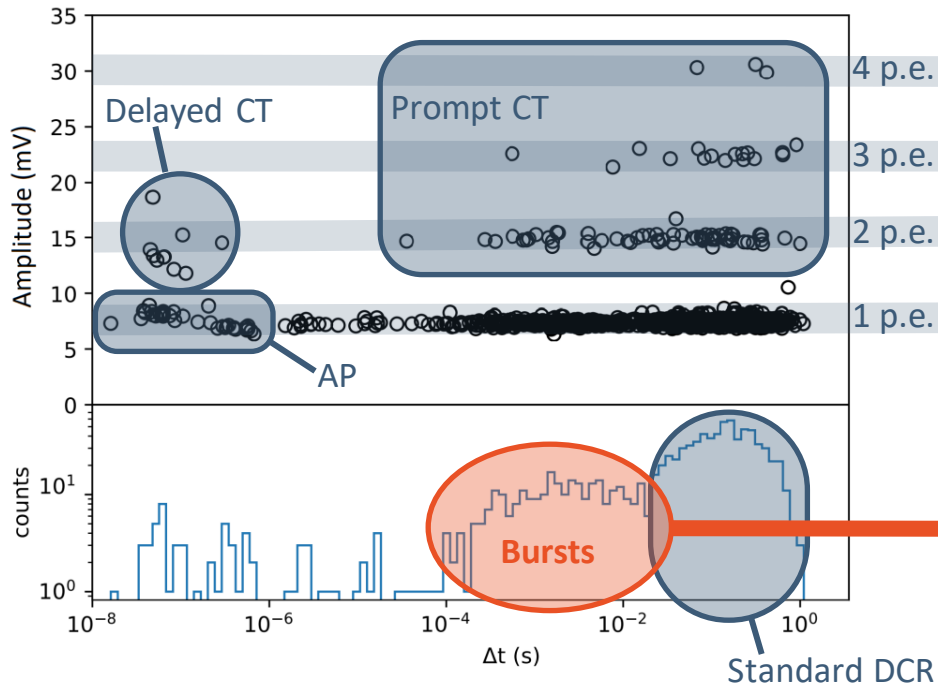
Custom **offline analysis** to extrapolate DCR, CT and AP values in two steps:

Event isolation

- Peak signals identification
- Extract amplitudes and relative times

DCR analysis

- Calculates DCR, AP and CT by counting events

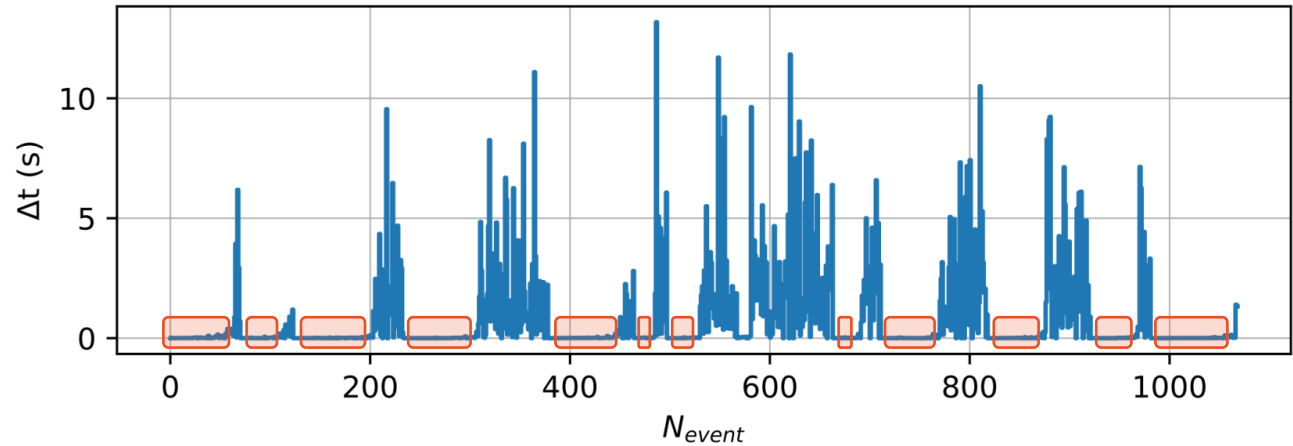


Quick trains of correlated events

Currently under investigations...

Results: burst analysis

Bursts are also distinguishable as valleys in the time trend distribution



- Burst observed in many tested SiPM models
- their randomness brings the DCR to unpredictable values
- **Burts-independent parameter** needed to compare different SiPMs

This quantity is the standard DCR, without the burst contribution

Two algorithms to distinguish burst contribution from standard DCR:

- **tag method**
- **fit method**

Results: burst analysis

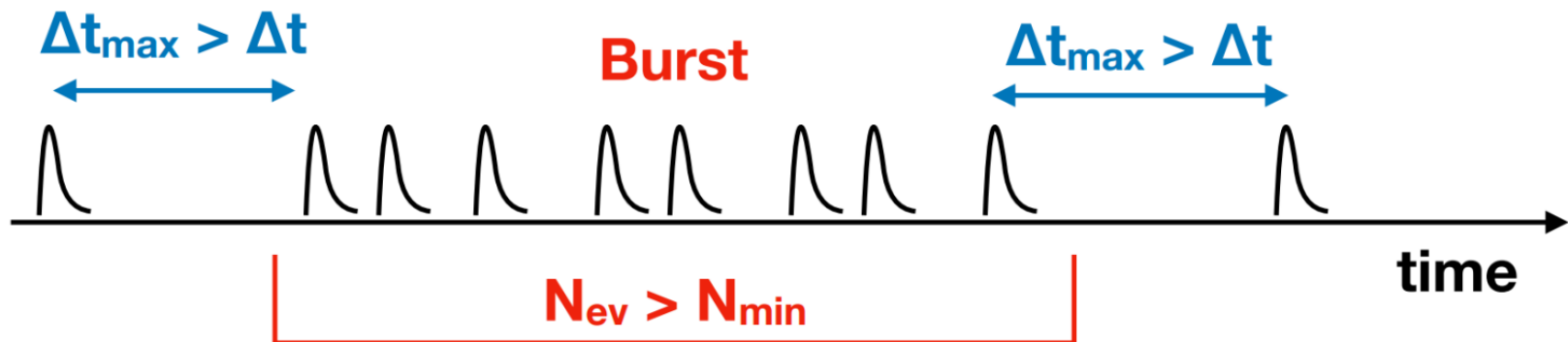
Tag method

Isolates the burst's events one by one, finding fast consecutive events:

- Time-interval Δt higher than typical AP time
- Δt lower than t_{\max} (typically $6 \mu\text{s}$)
- Number of consecutive events N_{ev} larger than N_{min} , (typically 5)

Best values for found by:

- tuning these parameters
- cross-checking the data

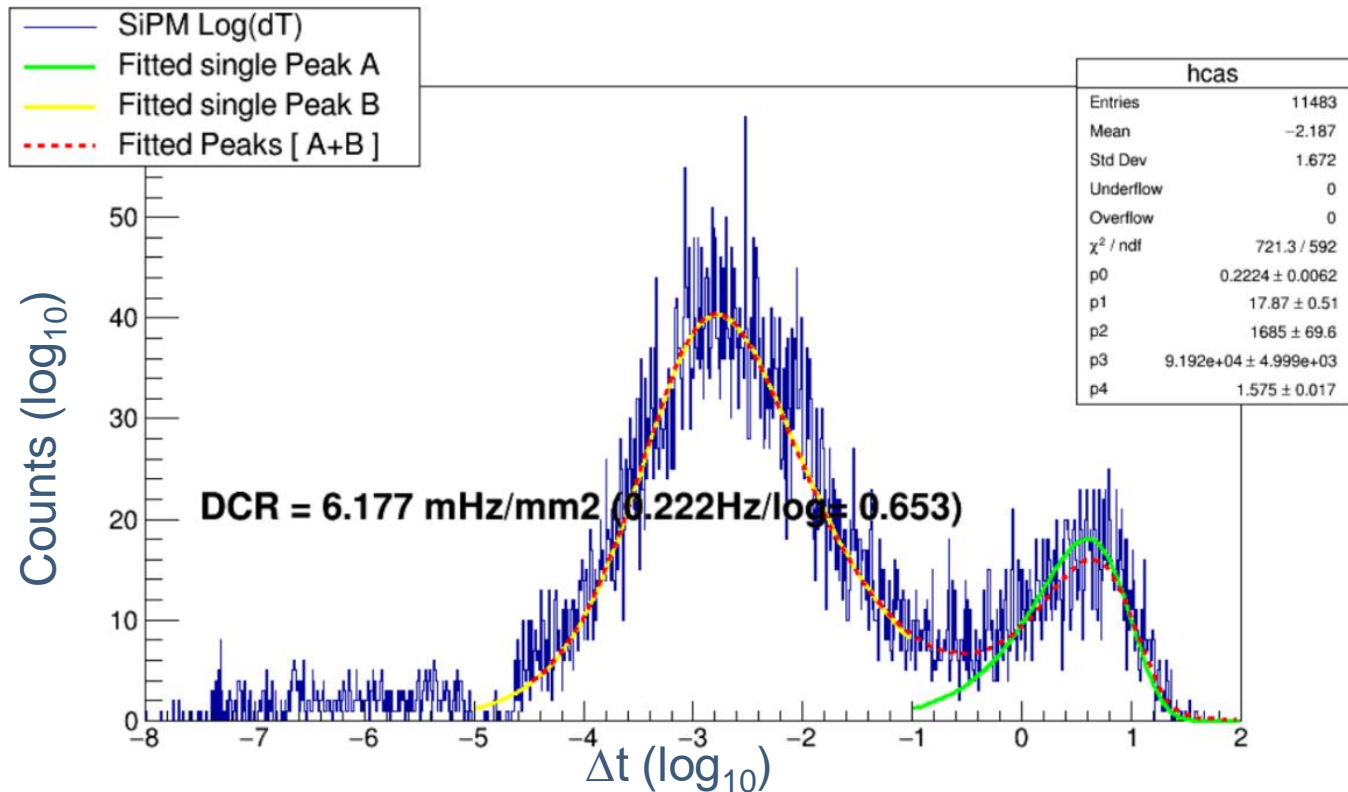


Results: burst analysis

Fit method

Both conceptually and practically different.

It is a fit of the time-trend histogram of the events, as shown in figure.



Functions:

- Poissonian distribution for uncorrelated DCR, $\Delta t = [0.1 - 100]$ s,
- Over-dispersed Poissonian, $\Delta t = [10^{-5} - 10^{-1}]$ s for burst contribution

Results: burst analysis

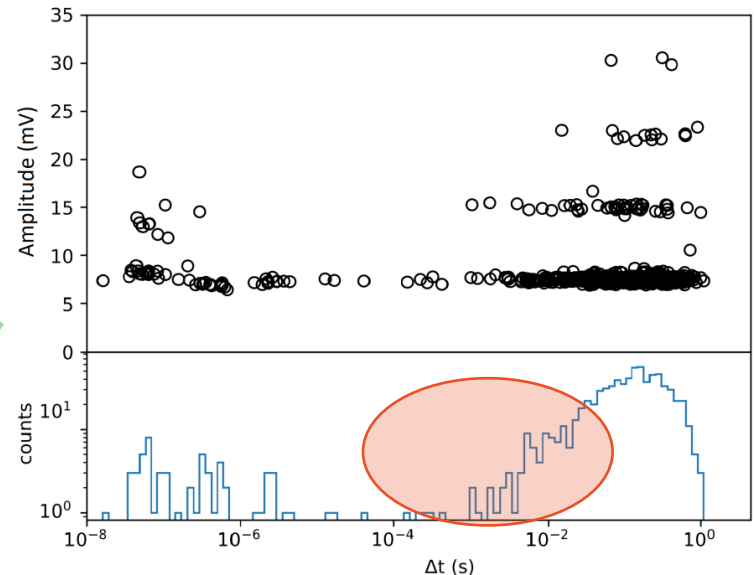
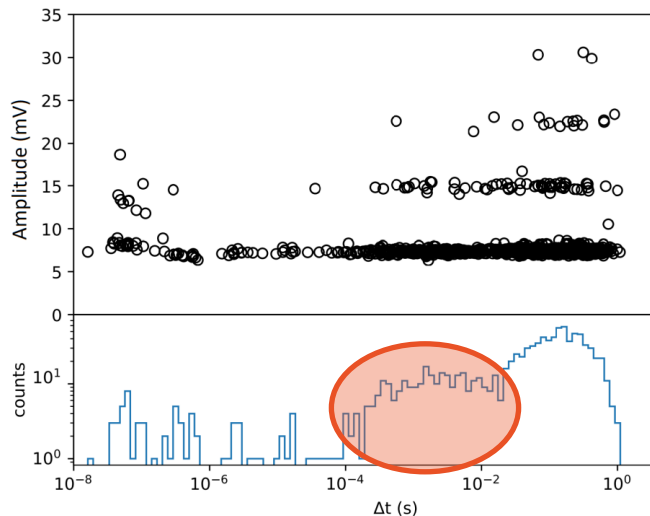
DCR extracted with the two methods in agreement with each other

Different features of the methods

- Fit method faster due to direct fit on the histogram
- Tag method, deep analysis of single events within the bursts

Common features emerged studying the burst events more in details:

- Last for a few tenths of a second
- Events separated by a [0.1-10] ms time delay
- Often triggered by a high-amplitude event
- Almost a hundred of events per burst



Conclusions and perspectives

- ProtoDUNE2-SP PD system based on SiPMs, as these devices are ideal for low photon count applications
- Thanks to custom experimental setup, full characterization of all SiPMs at cryogenic T accomplished. Results well within the DUNE specs but DCR higher due to unexpected burst phenomenon. Mass-test is ongoing...
- Custom algorithms to eliminate burst contribution from DCR and study burst behavior in more detail, further investigations are ongoing...